

N-channel TrenchMOS standard level FET 28 July 2016

Product data sheet

## 1. General description

Standard level N-channel MOSFET in a SOT404 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

## 2. Features and benefits

- AEC Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True standard level gate with VGS(th) rating of greater than 1V at 175 °C

## 3. Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

## 4. Quick reference data

Table 1. Qui	ck reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	40	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>	[1]	-	-	75	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	-	182	W
Static characte	eristics		1			1	
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 11		-	3.3	4	mΩ
Dynamic chara	acteristics						,
Q <sub>GD</sub>	gate-drain charge	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; V <sub>DS</sub> = 32 V; <u>Fig. 13; Fig. 14</u>		-	15.5	-	nC

[1] Continuous current is limited by package.





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## 5. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		G-UTA
mb	D	mounting base; connected to drain	D2PAK (SOT404)	mbb076 S

## 6. Ordering information

Table 3. Ordering inf	Table 3. Ordering information					
Type number	Package					
	Name	Description	Version			
BUK764R0-40E	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404			

## 7. Marking

Table 4. Marking codes	
Type number	Marking code
BUK764R0-40E	BUK764R0-40E

## 8. Limiting values

#### Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	40	V
V <sub>DGR</sub>	drain-gate voltage	R <sub>GS</sub> = 20 kΩ		-	40	V
V <sub>GS</sub>	gate-source voltage	T <sub>j</sub> ≤ 175 °C; DC		-20	20	V
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	182	W
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; <u>Fig. 2</u>	[1]	-	75	А
		T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 10 V; <u>Fig. 2</u>	[1]	-	75	А
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; Fig. 3		-	620	А
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
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## **BUK764R0-40E**

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Symbol	Parameter	Conditions		Min	Мах	Unit
Source-drain	diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	[1]	-	75	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	620	А
Avalanche ru	uggedness			1		
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\label{eq:ID} \begin{array}{l} {\sf I}_D = 75 \; {\sf A}; \; {\sf V}_{sup} \le 40 \; {\sf V}; \; {\sf R}_{GS} = 50 \; \Omega; \\ {\sf V}_{GS} = 10 \; {\sf V}; \; {\sf T}_{j(init)} = 25 \; {\rm ^\circ C}; \; unclamped; \\ \hline {\sf Fig. 4} \end{array}$	[2][3]	-	302	mJ

[1]

Continuous current is limited by package. Single-pulse avalanche rating limited by maximum junction temperature of 175 °C. [2]

[3] Refer to application note AN10273 for further information.

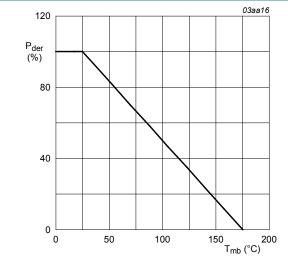
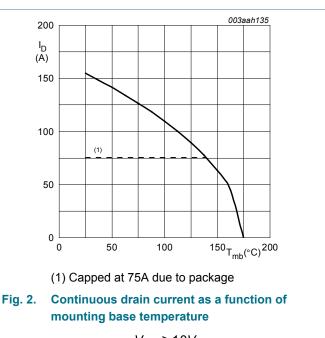


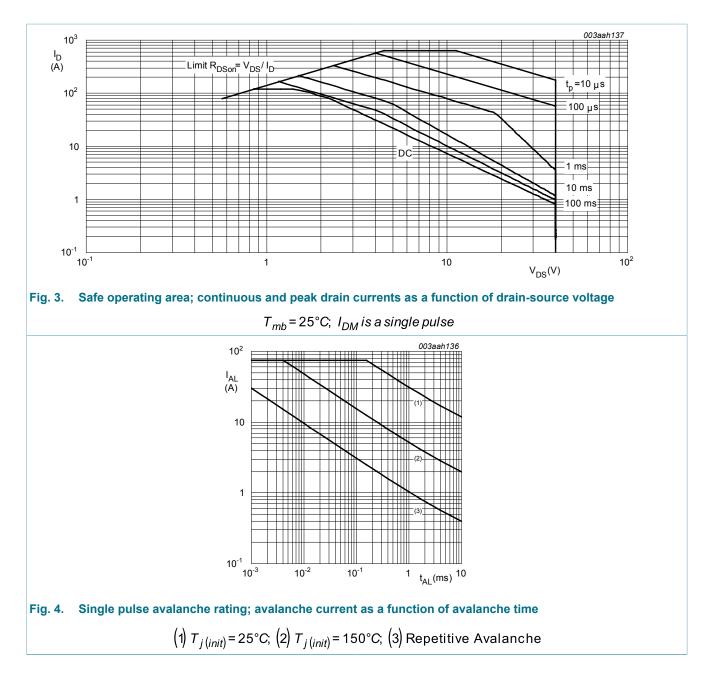
Fig. 1. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$



 $V_{GS} \ge 10V$ 

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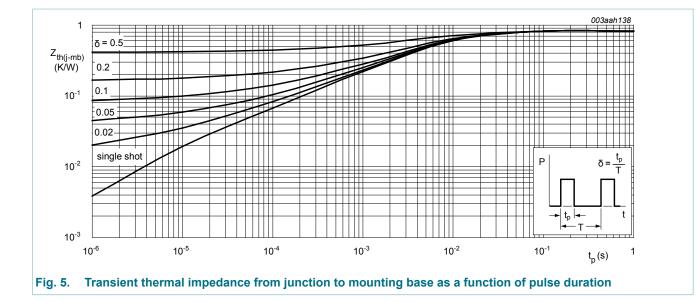
## 9. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	<u>Fig. 5</u>	-	-	0.82	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	minimum footprint; mounted on a printed-circuit board	-	50	-	K/W

#### Table 6. Thermal characteristics

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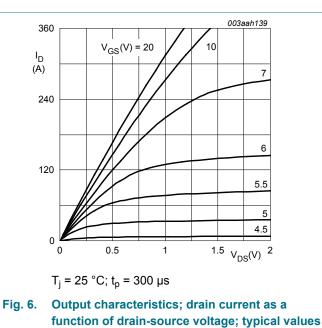


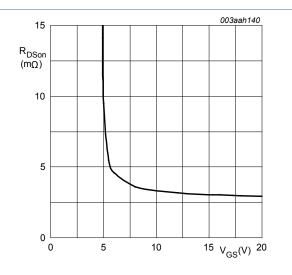
## **10.** Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C	40	-	-	V
	breakdown voltage	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = -55 °C	36	-	-	V
/ <sub>GS(th)</sub> gate-source threshold voltage		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ Fig. 9; Fig. 10	2.4	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ Fig. 10	-	3       4         -       4.5         -       4.5         0.12       1         -       500         2       100         3.3       4	V	
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175 °C; Fig. 10	1	-	- V 2 1 μ/ 500 μ/ 100 n/	V
I <sub>DSS</sub> drain leakage current	$V_{DS}$ = 40 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	0.12	1	μA	
		$V_{DS}$ = 40 V; $V_{GS}$ = 0 V; $T_j$ = 175 °C	-	-	500	μA
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = 20 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
		$V_{GS}$ = -20 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	3.3	4	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; Fig. 12; Fig. 11	-	-	7.6	mΩ
Dynamic cl	naracteristics	· · ·	I.			_
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	54	-	nC
Q <sub>GS</sub>	gate-source charge	<u>Fig. 13; Fig. 14</u>	-	13.6	-	nC
Q <sub>GD</sub>	gate-drain charge	1	-	15.5	-	nC

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Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; Fig. 15$ $V_{DS} = 30 \text{ V}; R_{L} = 1.2 \Omega; V_{GS} = 10 \text{ V};$ $R_{G(ext)} = 5 \Omega$ from upper edge of drain mounting base to center of die from source lead to source bonding pad e $I_{S} = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_{j} = 25 \text{ °C}; Fig. 16$ ne $I_{S} = 20 \text{ A}; dI_{S}/dt = -100 \text{ A}/\mu\text{s}; V_{GS} = 0 \text{ V};$	-	3304	4405	pF
C <sub>oss</sub>	output capacitance		-	634	761	pF
C <sub>rss</sub>	reverse transfer capacitance		-	333	456	pF
t <sub>d(on)</sub>	turn-on delay time	$R_{G(ext)} = 5 \Omega$	-	22	-	ns
t <sub>r</sub>	rise time		-	20	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	43	-	ns
t <sub>f</sub>	fall time		-	20	-	ns
L <sub>D</sub>	internal drain inductance		-	2.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bonding pad	-	7.5	-	nH
Source-dra	in diode	· · · · · · · · · · · · · · · · · · ·	1			,
V <sub>SD</sub>	source-drain voltage	$I_{S}$ = 25 A; $V_{GS}$ = 0 V; $T_{j}$ = 25 °C; <u>Fig. 16</u>	-	0.84	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{\rm S}$ = 20 A; dI <sub>S</sub> /dt = -100 A/µs; V <sub>GS</sub> = 0 V;	-	31.1	-	ns
Q <sub>r</sub>	recovered charge	V <sub>DS</sub> = 25 V	-	28.9	-	nC



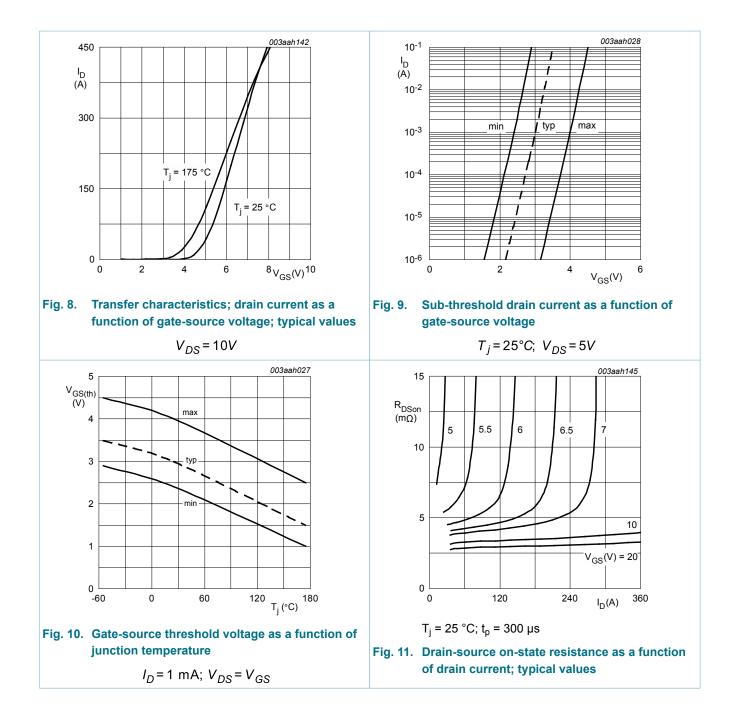




 $T_j = 25^{\circ}C; I_D = 25A$ 

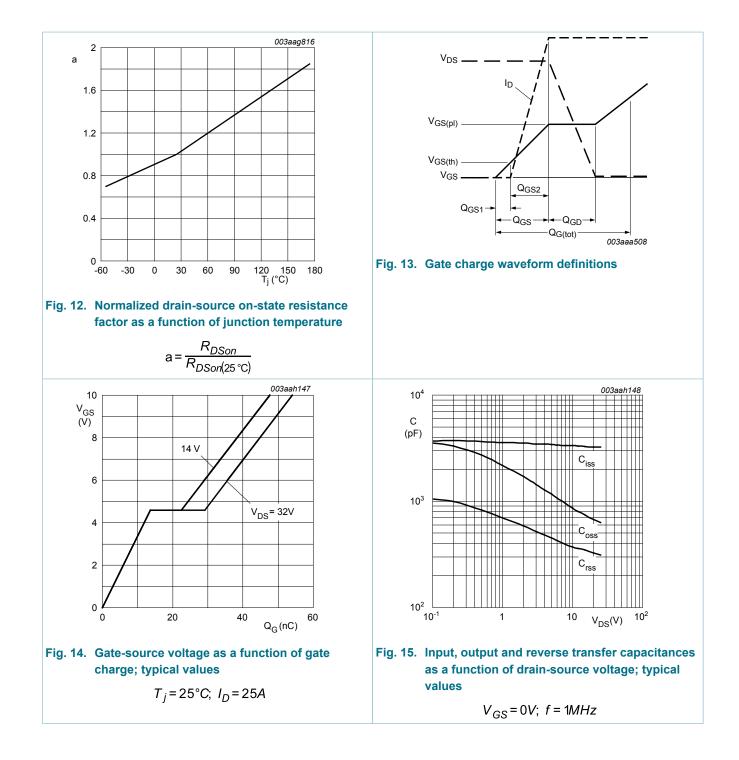
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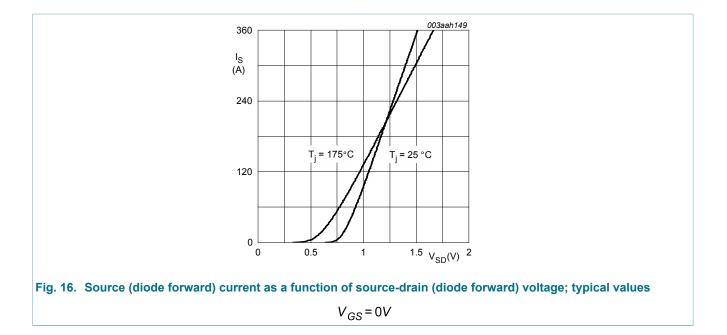
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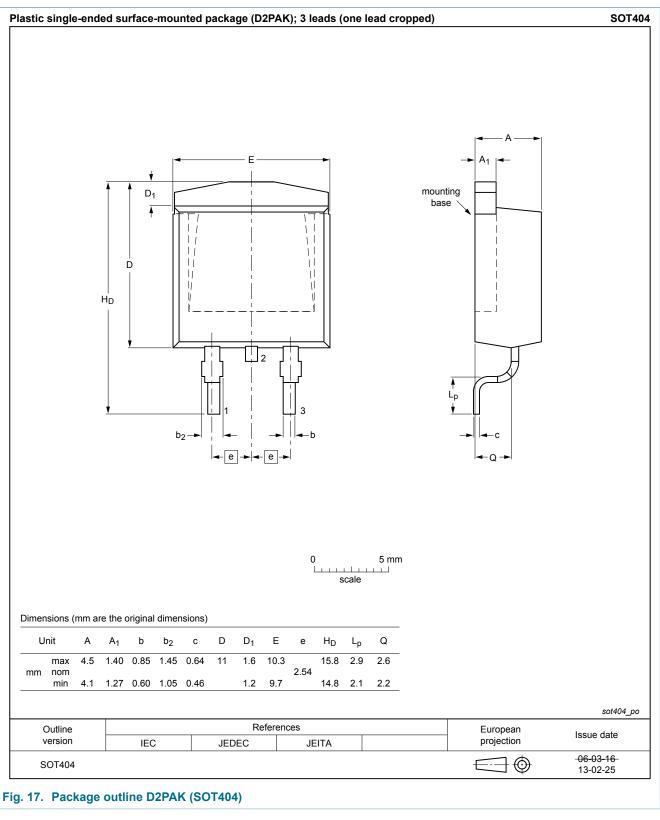
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### 11. Package outline



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